

Notice of References Cited	Application/Control No. 10/811,918	Applicant(s)/Patent Under Reexamination ONO ET AL.	
	Examiner Rodney H. Bonck	Art Unit 3681	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0175037 A1	11-2002	Wack et al.	192/3.29
	B	US-6,267,213	07-2001	Yamaguchi et al.	192/3.29
	C	US-6,712,186	03-2004	Arhab, Rabah	192/3.29
	D	US-6,193,037	02-2001	Middelmann et al.	192/3.29
	E	US-6,708,804	03-2004	Krause et al.	192/3.29
	F	US-6,062,358	05-2000	Otto et al.	192/3.29
	G	US-5,868,228	02-1999	Fukushima, Hirota	192/3.29
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2001-355703 A	12-2001	Japan	Kawamoto et al.	-----
	O	JP 9-133197 A	05-1997	Japan	Fujimoto, S.	-----
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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